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Practice quiz ion beam etching

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Questions:

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1. What is the main advantage of Ion Beam Etching (IBE) to a plasma-based etching process?

- ☐ High-aspect ratio structures can only be fabricated by IBE
- ☐ The pulsed deep dry etching process of Si (Bosch process) is only possible by using IBE
- ☒ The angle of incidence of the ion beam onto the sample can be varied and etching profiles with different angles with respect to the surface can be fabricated
- ☐ The power consumption is extremely low



Explanation

Inside an Ion Beam Etcher (IBE), it is easy to vary the angle of incidence of the ion beam onto the sample, which is impossible in a plasma-based process. This is the main advantage of this tool to plasma-based etching processes. See "Ion beam etching" video from 0:15 to 1:05 for more detailed explanations.

2. Which of the following is a limitation of IBE?

- ☐ There are a lot of collisions of ions among themselves during their transport, which sometimes damage the sample surface
- ☐ Operation pressure is quite high, which causes instability of long etching processes
- ☐ The sputtered material redeposits on the sample surface if the operation pressure is kept too low
- ☒ Etching processes which consume or generate a significant quantity of gas are not possible



Explanation

There are certain limitations of IBE which are a consequence of limited gas flow at an operating pressure of 0.1 mbar. In sensitive processes, to maintain the etch rate, a high ion flux is needed, which is difficult to obtain with a remote ion source. Additionally, etching processes that consume or generate a significant quantity of gas are not possible. See "Ion beam etching" video from 4:30 to 5:30 for more detailed explanations.

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Answers are displayed within the problem

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